

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination HAN ET AL.	
		Examiner Nathan W. Ha	Art Unit 2814	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0070001 A1	04-2004	Lee et al.	257/099
	B	US-6,746,295 B2	06-2004	Sorg, Jorg-Erich	445/24
	C	US-6,774,405 B2	08-2004	Yasukawa et al.	257/99
	D	US-6,608,334 B1	08-2003	Ishinaga, Hiroki	257/100
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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